# **Electronic Supplementary Information**

# Heterobimetallic Cerium(IV) Oxo Clusters Supported by a

# **Tripodal Oxygen Ligand**

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- 1. NMR and IR spectra of **3** and **4**
- 2. MALDI mass spectrum of **4**
- 3. X-ray photoelectron spectrum of 4

## 1. NMR and IR Spectra of **3** and **4**

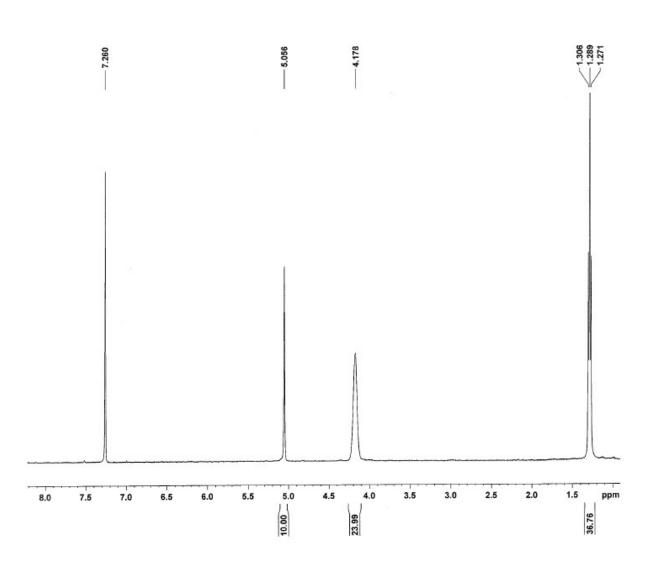


Figure S1. <sup>1</sup>H NMR (400 MHz, 25 °C) spectrum of 3 in CDCl<sub>3</sub>.

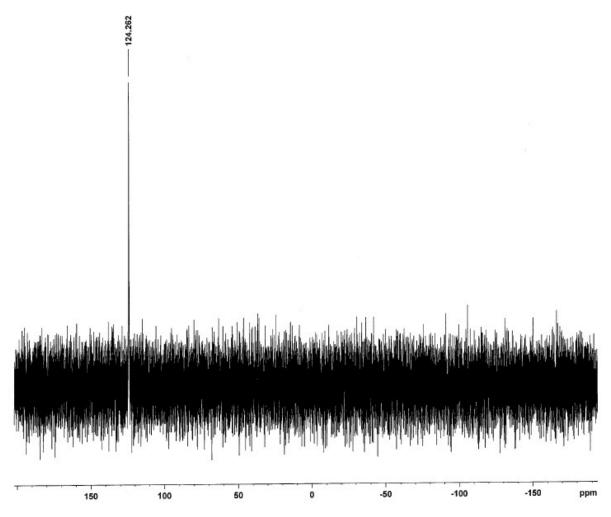


Figure S2. <sup>31</sup>P {<sup>1</sup>H} NMR (162 MHz, 25 °C) spectrum of 3 in CDCl<sub>3</sub>.

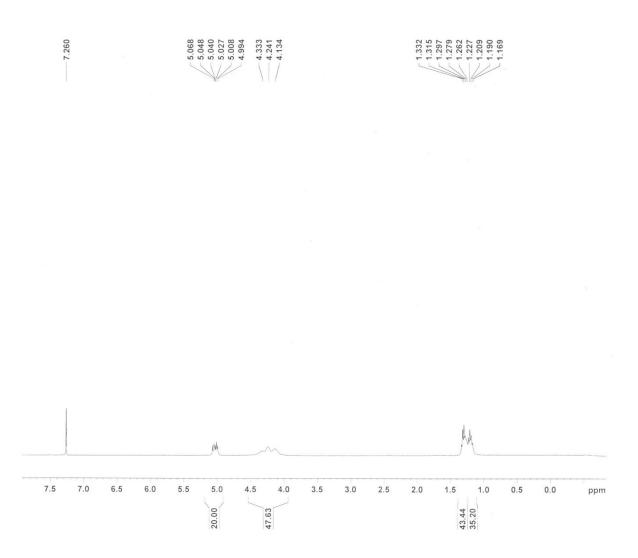


Figure S3. <sup>1</sup>H NMR (400 MHz, 25 °C) spectrum of 4 in CDCl<sub>3</sub>.

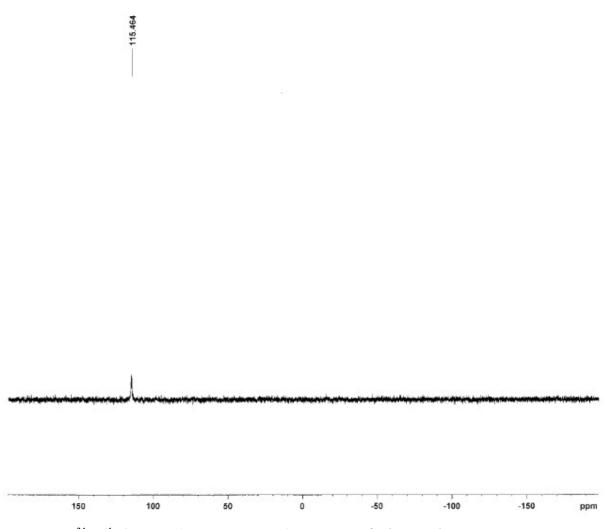
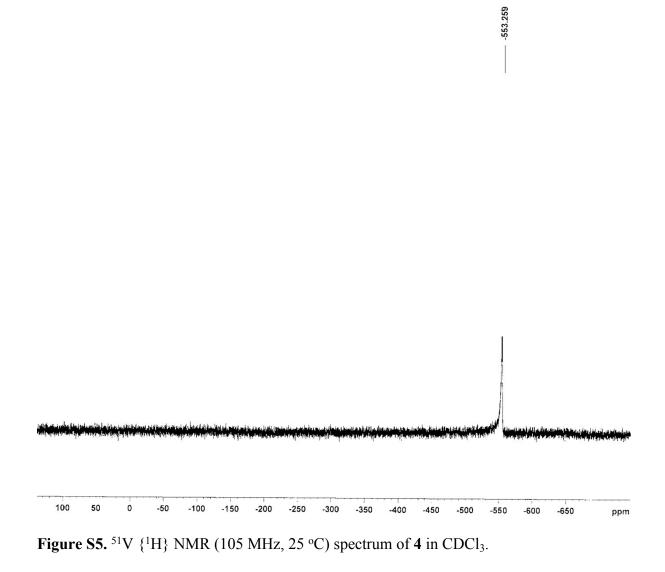
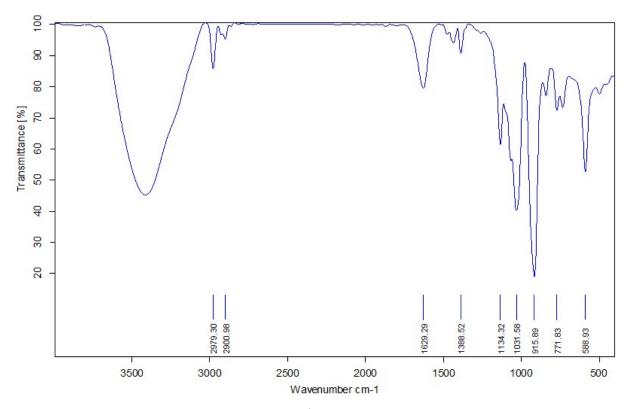


Figure S4. <sup>31</sup>P {<sup>1</sup>H} NMR (162 MHz, 25 °C) spectrum of 4 in CDCl<sub>3</sub>.





**Figure S6**. IR (KBr) spectrum (400-4000 cm<sup>-1</sup> region) of **3**.

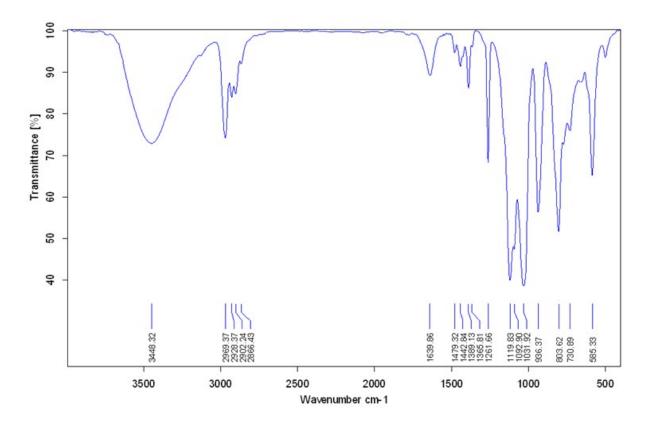
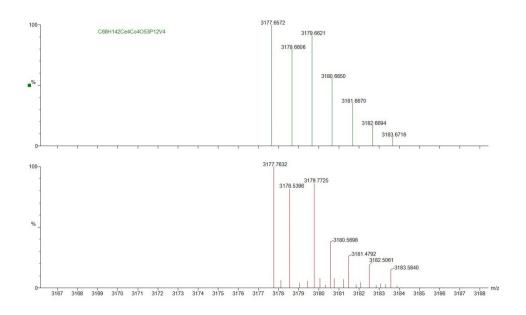
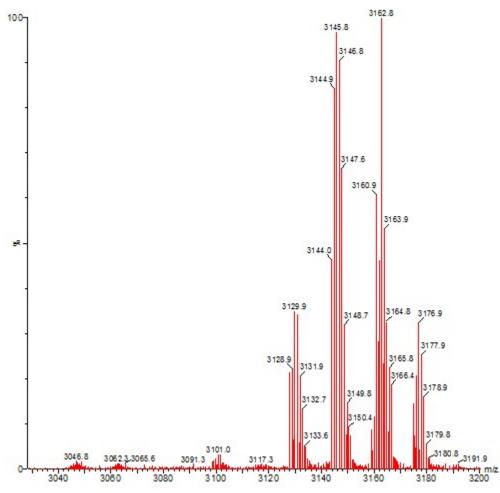


Figure S7. IR (KBr) spectrum (400-4000 cm<sup>-1</sup> region) of 4.

### 2. Mass Spectra of 4



**Figure S8.** The [M]<sup>+</sup> signal in the MALDI mass spectrum of **4** (bottom) and the simulated spectrum (top).



**Figure S9.** MALDI mass spectrum (m/z = 3020 - 3200) of the reaction mixture after the catalytic oxidation of methyl *p*-tolylsulfide with **4** and TBHP in CH<sub>2</sub>Cl<sub>2</sub>.

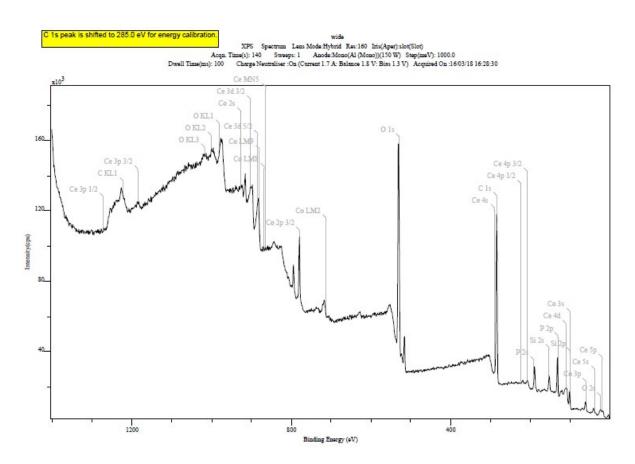


Figure S10. Full XPS spectrum of 4

The XPS spectrum was obtained on Kratos Axis Ultra DLD instrument.

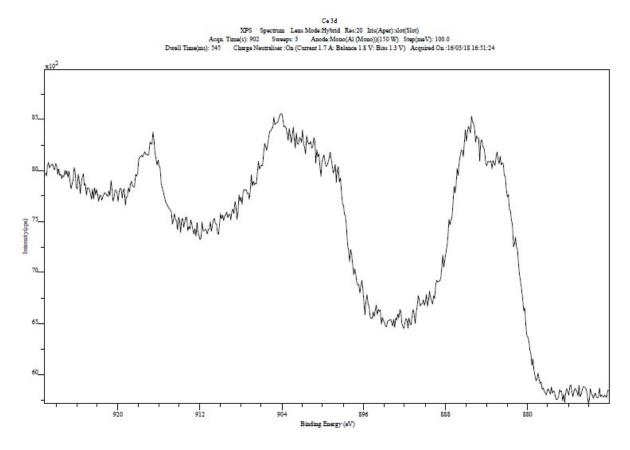


Figure S11. Ce region of the XPS spectrum of 4

The observed signal at ca. 916 eV is characteristic of Ce(IV) (cf. lit. 917 eV<sup>a</sup>). The absence of signal at ca. 880 eV indicates the absence of Ce(III) in **4**.

<sup>a</sup>Beche et al., Surf. Interface Anal. 2008, **40**, 264–267.

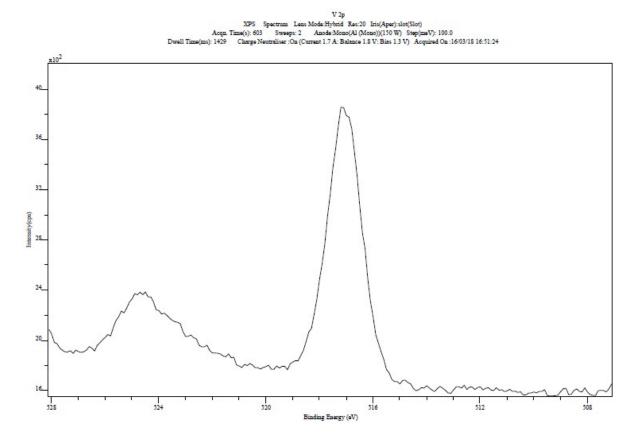


Figure S12. V region of the XPS spectrum of 4

The peaks at ca. 516.5 (V  $2p_{3/2}$ ) and 524.5 (V  $2p_{1/2}$ ) eV are characteristic of V(V) (cf. lit. 517 and 525 eV,<sup>b,c</sup> respectively).

<sup>b</sup> C. D. Wagner, A. V. Naumkin, A. Kraut-Vass, J. W. Allison, C. J. Powell, J. R. Jr. Rumble, *NIST Standard Reference Database 20*, Version 3.4 (http://srdata.nist.gov/xps/) 2003.

<sup>c</sup> M. C. Biesinger, L. W. M. Lau, A. R. Gerson, R. St. C. Smart, Resolving Surface Chemical States in XPS Analysis of First Row Transition Metals, Oxides and Hydroxides: Sc, Ti, V, Cu and Zn, *Applied Surface Science*, 2010, **257**, 887–898.